

Applications

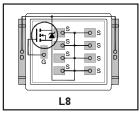
- RoHS Compliant, Halogen Free 2
- Lead-Free (Qualified up to 260°C Reflow) 1
- Ideal for High Performance Isolated Converter Primary Switch Socket
- Optimized for Synchronous Rectification
- Low Conduction Losses
- High Cdv/dt Immunity
- Low Profile (<0.7mm)
- Dual Sided Cooling Compatible ①
- Compatible with existing Surface Mount Techniques ①
- Industrial Qualified

Applicable DirectFET Outline and Substrate Outline 1

<u>DirectFET™ Power MOSFET</u> ②

Typical values (unless otherwise specified)

V _{DSS}	V _{GS}	R _{DS(on)}
40V min	±20V max	$0.70 \text{m}\Omega$ @ 10V
		W
\mathbf{Q}_{gtot}	\mathbf{Q}_{gd}	$V_{gs(th)}$





SB SC M2 M4 L4 L6 L8

Description

The IRF7739L1TRPbF combines the latest HEXFET® Power MOSFET Silicon technology with the advanced DirectFET $^{\text{TM}}$ packaging to achieve the lowest on-state resistance in a package that has a footprint smaller than a D 2 PAK and only 0.7 mm profile. The DirectFET package is compatible with existing layout geometries used in power applications, PCB assembly equipment and vapor phase, infra-red or convection soldering techniques, when <u>application note AN-1035</u> is followed regarding the manufacturing methods and processes. The DirectFET package allows dual sided cooling to maximize thermal transfer in power systems.

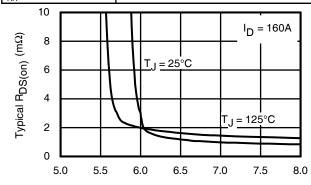
The IRF7739L1TRPbF is optimized for high frequency switching and synchronous rectification applications. The reduced total losses in the device coupled with the high level of thermal performance enables high efficiency and low temperatures, which are key for system reliability improvements, and makes this device ideal for high performance power converters.

Ordering Information

Base part number	Package Type	Sta	ndard Pack	Orderable Part Number	
		Form	Quantity		
IRF7739L1TRPbF	DirectFET Large Can	Tape and Reel	4000	IRF7739L1TRPbF	

Absolute Maximum Ratings

	Parameter	Max.	Units
V _{DS}	Drain-to-Source Voltage	40	V
V _{GS}	Gate-to-Source Voltage	±20	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) ^④	270	
D @ T _C = 100°C Continuous Drain Current, V _{GS} @ 10V (Silicon Limited)		190	Α
I _D @ T _A = 25°C	Continuous Drain Current, V _{GS} @ 10V (Silicon Limited) ^③	46	
I _D @ T _C = 25°C	Continuous Drain Current, V _{GS} @ 10V (Package Limited) ^④	375	
I _{DM}	Pulsed Drain Current ©	1070	
E _{AS}	Single Pulse Avalanche Energy ®	270	mJ
I _{AB}	Avalanche Current ⑤	160	Α



- $\rm V_{GS,}$ Gate -to -Source Voltage (V) Fig 1. Typical On-Resistance vs. Gate Voltage
 - Voltage
- ① Click on the hyperlink (to the relevant technical document) for more details. ② Click on the hyperlink (to the DirectFET website) for more details
- 3 Surface mounted on 1 in. square Cu board, steady state.
- 0.93 $V_{GS} = 10V$ 0.92 Typical RDS (on) ($^{M}\Omega$) 0.91 0.90 0.89 0.88 0.87 0.86 0.85 40 80 120 160 200 ID, Drain Current (A)

Fig 2. Typical On-Resistance vs. Drain Current

- $\ensuremath{\mathfrak{A}}$ T_C measured with thermocouple mounted to top (Drain) of part.
- © Repetitive rating; pulse width limited by max. junction temperature.
- $\ \, \text{ \fontfamily Starting T}_J = 25^{\circ}\text{C}, \ L = 0.021\text{mH}, \ R_G = 25\Omega, \ I_{AS} = 160\text{A}.$

Notes:



Static @ $T_J = 25$ °C (unless otherwise specified)

Parameter	Min.	Тур.	Max.	Units	Conditions
Drain-to-Source Breakdown Voltage	40			V	$V_{GS} = 0V, I_D = 250\mu A$
Breakdown Voltage Temp. Coefficient		0.008		V/°C	Reference to 25°C, I _D = 1.0mA
Static Drain-to-Source On-Resistance		0.70	1.0	mΩ	V _{GS} = 10V, I _D = 160A ⑦
Gate Threshold Voltage	2.0	2.8	4.0	V	$V_{DS} = V_{GS}$, $I_D = 250\mu A$
Gate Threshold Voltage Coefficient		-6.7		mV/°C	
Drain-to-Source Leakage Current			20	μΑ	$V_{DS} = 40V, V_{GS} = 0V$
			250		$V_{DS} = 32V, V_{GS} = 0V, T_{J} = 125^{\circ}C$
Gate-to-Source Forward Leakage			100	nA	V _{GS} = 20V
Gate-to-Source Reverse Leakage			-100		V _{GS} = -20V
Forward Transconductance	280			S	$V_{DS} = 10V, I_{D} = 160A$
Total Gate Charge		220	330		
Pre-Vth Gate-to-Source Charge		46			$V_{DS} = 20V$
Post-Vth Gate-to-Source Charge		19		nC	$V_{GS} = 10V$
Gate-to-Drain Charge		81	120		I _D = 160A
Gate Charge Overdrive		74			See Fig. 9
Switch Charge (Q _{gs2} + Q _{gd})		100			
Output Charge		83		nC	$V_{DS} = 16V, V_{GS} = 0V$
Gate Resistance		1.5		Ω	
Turn-On Delay Time		21			$V_{DD} = 20V, V_{GS} = 10V$ ⑦
Rise Time		71			I _D = 160A
Turn-Off Delay Time		56		ns	$R_G=1.8\Omega$
Fall Time		42			
Input Capacitance		11880			$V_{GS} = 0V$
Output Capacitance		2510		pF	$V_{DS} = 25V$
Reverse Transfer Capacitance		1240			f = 1.0MHz
Output Capacitance		8610			$V_{GS} = 0V, V_{DS} = 1.0V, f=1.0MHz$
Output Capacitance		2230			$V_{GS} = 0V, V_{DS} = 32V, f=1.0MHz$
	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Gate Threshold Voltage Coefficient Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Forward Transconductance Total Gate Charge Pre-Vth Gate-to-Source Charge Post-Vth Gate-to-Source Charge Gate-to-Drain Charge Gate Charge Overdrive Switch Charge (Q _{gs2} + Q _{gd}) Output Charge Gate Resistance Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance Output Capacitance	Drain-to-Source Breakdown Voltage Breakdown Voltage Temp. Coefficient Static Drain-to-Source On-Resistance Gate Threshold Voltage Gate Threshold Voltage Coefficient Drain-to-Source Leakage Current Gate-to-Source Forward Leakage Gate-to-Source Reverse Leakage Forward Transconductance Total Gate Charge Pre-Vth Gate-to-Source Charge Gate-to-Drain Charge Gate Charge Overdrive Switch Charge (Q _{gs2} + Q _{gd}) Output Charge Gate Resistance Turn-On Delay Time Rise Time Turn-Off Delay Time Fall Time Input Capacitance Output Capacitance Reverse Transfer Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance Output Capacitance —— Output Capacitance	Drain-to-Source Breakdown Voltage 40 — Breakdown Voltage Temp. Coefficient — 0.008 Static Drain-to-Source On-Resistance — 0.70 Gate Threshold Voltage 2.0 2.8 Gate Threshold Voltage Coefficient — -6.7 Drain-to-Source Leakage Current — — — — — — Gate-to-Source Forward Leakage — — — Gate-to-Source Forward Leakage — — — Forward Transconductance 280 — — Forward Transconductance 280 — — Total Gate Charge — 220 — — 46 Post-Vth Gate-to-Source Charge — 46 — — 19 Gate-to-Drain Charge — 81 — — 74 Switch Charge Overdrive — 74 Switch Charge (Q _{gs2} + Q _{gd}) — 100 — 100 Output Charge — 83 Gate Resistance — 1.5	Drain-to-Source Breakdown Voltage 40 — — Breakdown Voltage Temp. Coefficient — 0.008 — Static Drain-to-Source On-Resistance — 0.70 1.0 Gate Threshold Voltage 2.0 2.8 4.0 Gate Threshold Voltage Coefficient — -6.7 — Drain-to-Source Leakage Current — — 20 — — 250 Gate-to-Source Forward Leakage — — 100 Gate-to-Source Reverse Leakage — — 100 Forward Transconductance 280 — — Total Gate Charge — 220 330 Pre-Vth Gate-to-Source Charge — 46 — Post-Vth Gate-to-Source Charge — 19 — Gate-to-Drain Charge — 81 120 Gate Charge Overdrive — 74 — Switch Charge (Q _{gs2} + Q _{gd}) — 100 — Output Charge — 1.5 — </td <td>Drain-to-Source Breakdown Voltage 40 — V Breakdown Voltage Temp. Coefficient — 0.008 — V/°C Static Drain-to-Source On-Resistance — 0.70 1.0 mΩ Gate Threshold Voltage 2.0 2.8 4.0 V Gate Threshold Voltage Coefficient — -6.7 — mV/°C Drain-to-Source Leakage Current — -6.7 — mV/°C Drain-to-Source Leakage Current — -6.7 — mV/°C Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 100 nA Forward Transconductance 280 — — S Total Gate Charge — 46 — N nC Forward Transconductance — 46 — N nC nC Total Gate Charge — 46 — — nC nC nC nC nC nC</td>	Drain-to-Source Breakdown Voltage 40 — V Breakdown Voltage Temp. Coefficient — 0.008 — V/°C Static Drain-to-Source On-Resistance — 0.70 1.0 mΩ Gate Threshold Voltage 2.0 2.8 4.0 V Gate Threshold Voltage Coefficient — -6.7 — mV/°C Drain-to-Source Leakage Current — -6.7 — mV/°C Drain-to-Source Leakage Current — -6.7 — mV/°C Gate-to-Source Forward Leakage — — 100 nA Gate-to-Source Reverse Leakage — — 100 nA Forward Transconductance 280 — — S Total Gate Charge — 46 — N nC Forward Transconductance — 46 — N nC nC Total Gate Charge — 46 — — nC nC nC nC nC nC

Diode Characteristics

	Parameter	Min.	Тур.	Max.	Units	Conditions
I _S	Continuous Source Current			110		MOSFET symbol
	(Body Diode)				Α	showing the
I _{SM}	Pulsed Source Current			1070		integral reverse
	(Body Diode) ⑤					p-n junction diode.
V _{SD}	Diode Forward Voltage			1.3	V	$T_J = 25^{\circ}C, I_S = 160A, V_{GS} = 0V ?$
t _{rr}	Reverse Recovery Time		87	130	ns	$T_J = 25^{\circ}C$, $I_F = 160A$, $V_{DD} = 20V$
Q _{rr}	Reverse Recovery Charge		250	380	nC	di/dt = 100A/µs ⑦

Notes:

⑤ Repetitive rating; pulse width limited by max. junction temperature.

 $[\]ensuremath{{\bigcirc}}$ Pulse width $\le 400 \mu s;$ duty cycle $\le 2\%.$



Absolute Maximum Ratings

	Parameter	Max.	Units
P _D @T _C = 25°C	Power Dissipation ®	125	W
P _D @T _C = 100°C	Power Dissipation ®	63	
$P_D @ T_A = 25^{\circ}C$	Power Dissipation ①	3.8	
T _P	Peak Soldering Temperature	270	°C
T_J	Operating Junction and	-55 to + 175	
T _{STG}	Storage Temperature Range		

Thermal Resistance

	Parameter	Тур.	Max.	Units
$R_{\omega A}$	Junction-to-Ambient ③		40	
$R_{\omega A}$	Junction-to-Ambient ®	12.5		
R _{eJA}	Junction-to-Ambient	20		°C/W
R _{W-Can}	Junction-to-Can @ ®	_	1.2	
R _{U-PCB}	Junction-to-PCB Mounted	_	0.4	

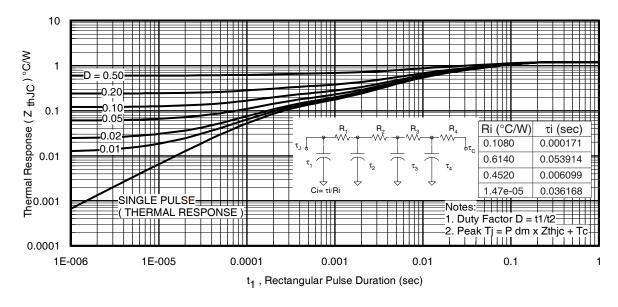
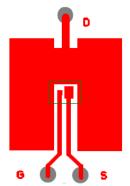


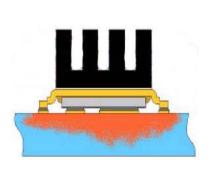
Fig 3. Maximum Effective Transient Thermal Impedance, Junction-to-Case @

Notes:

- 3 Surface mounted on 1 in. square Cu board, steady state.
- ④ T_C measured with thermocouple incontact with top (Drain) of part.
- ® Used double sided cooling, mounting pad with large heatsink.
- Mounted on minimum footprint full size board with metalized back and with small clip heatsink.
- $^{\circledR}$ R $_{\theta}$ is measured at T $_{J}$ of approximately 90°C.



3 Surface mounted on 1 in. square Cu board (still air).





 Mounted on minimum footprint full size board with metalized back and with small clip heatsink. (still air)

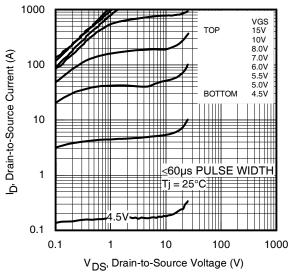


Fig 4. Typical Output Characteristics

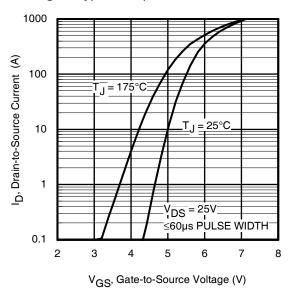


Fig 6. Typical Transfer Characteristics

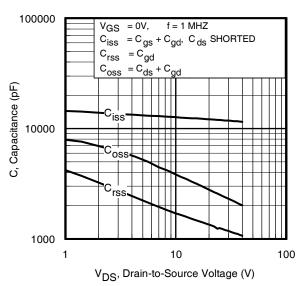


Fig 8. Typical Capacitance vs. Drain-to-Source Voltage

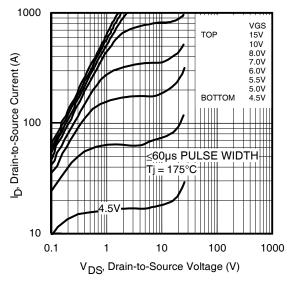


Fig 5. Typical Output Characteristics

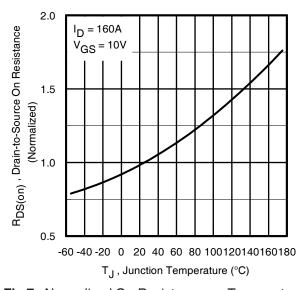


Fig 7. Normalized On-Resistance vs. Temperature

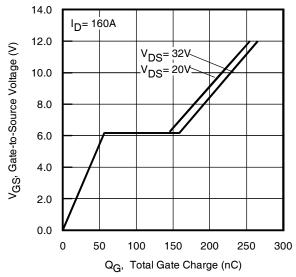


Fig 9. Typical Total Gate Charge vs. Gate-to-Source Voltage



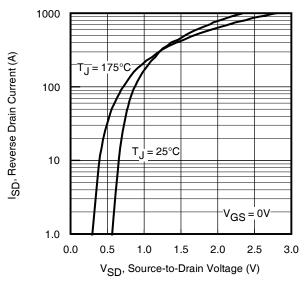


Fig 10. Typical Source-Drain Diode Forward Voltage

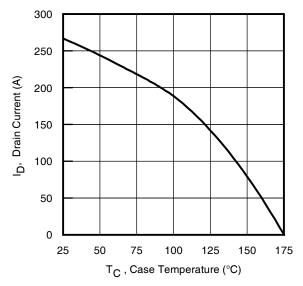


Fig 12. Maximum Drain Current vs. Case Temperature

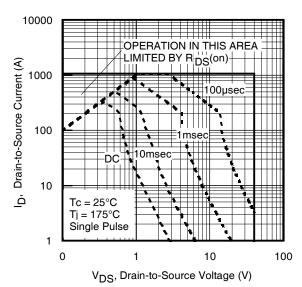


Fig11. Maximum Safe Operating Area

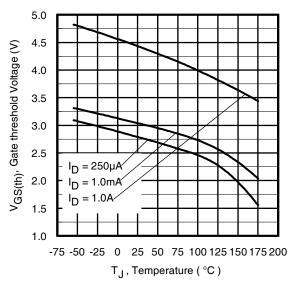


Fig 13. Typical Threshold Voltage vs. Junction Temperature

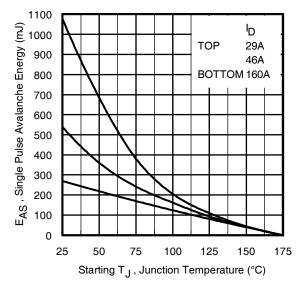


Fig 14. Maximum Avalanche Energy vs. Drain Current

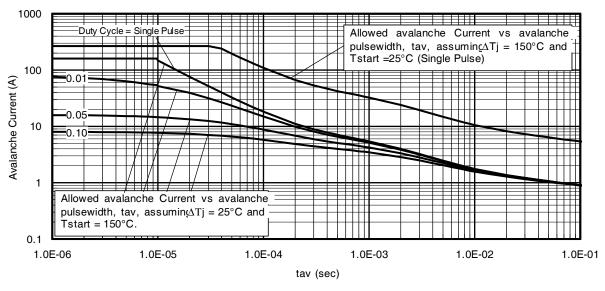


Fig 15. Typical Avalanche Current vs. Pulsewidth

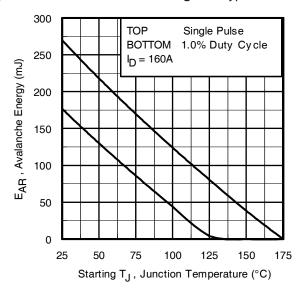
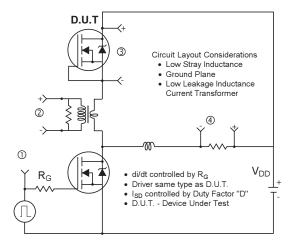


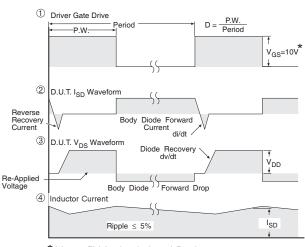
Fig 16. Maximum Avalanche Energy vs. Temperature

Notes on Repetitive Avalanche Curves , Figures 15, 16: (For further info, see <u>AN-1005</u>)

- Avalanche failures assumption: Purely a thermal phenomenon and failure occurs at a temperature far in excess of T_{jmax}. This is validated for every part type.
- Safe operation in Avalanche is allowed as long asT_{jmax} is not exceeded.
- Equation below based on circuit and waveforms shown in Figures 19a, 19b.
- 4. P_{D (ave)} = Average power dissipation per single avalanche pulse.
- 5. BV = Rated breakdown voltage (1.3 factor accounts for voltage increase during avalanche).
- 6. I_{av} = Allowable avalanche current.
- 7. ΔT = Allowable rise in junction temperature, not to exceed T_{jmax} (assumed as 25°C in Figure 15, 16). t_{av} = Average time in avalanche.
 - D = Duty cycle in avalanche = $t_{av} \cdot f$
 - $Z_{thJC}(D, t_{av}) = Transient thermal resistance, see figure 11)$

$$\begin{split} P_{D \; (ave)} = 1/2 \; (\; 1.3 \cdot \text{BV} \cdot \text{I}_{av}) &= \triangle \text{T} / \; \text{Z}_{thJC} \\ \text{I}_{av} = 2 \triangle \text{T} / \; [1.3 \cdot \text{BV} \cdot \text{Z}_{th}] \\ \text{E}_{AS \; (AR)} = P_{D \; (ave)} \cdot \text{t}_{a} \end{split}$$





* V_{GS} = 5V for Logic Level Devices

Fig 17. Diode Reverse Recovery Test Circuit for N-Channel HEXFET® Power MOSFETs



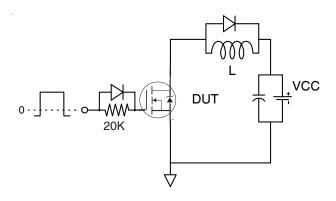


Fig 18a. Gate Charge Test Circuit

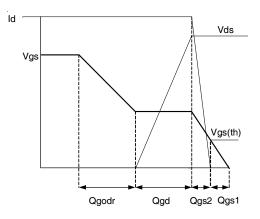


Fig 18b. Gate Charge Waveform

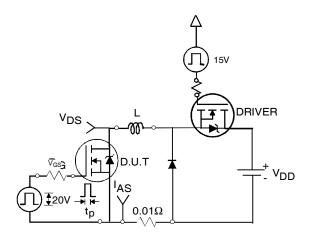


Fig 19a. Unclamped Inductive Test Circuit

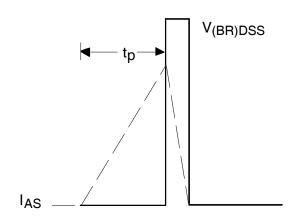


Fig 19b. Unclamped Inductive Waveforms

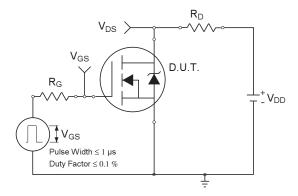


Fig 20a. Switching Time Test Circuit

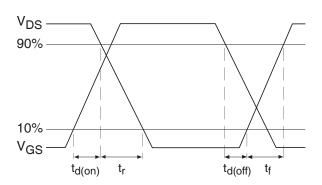
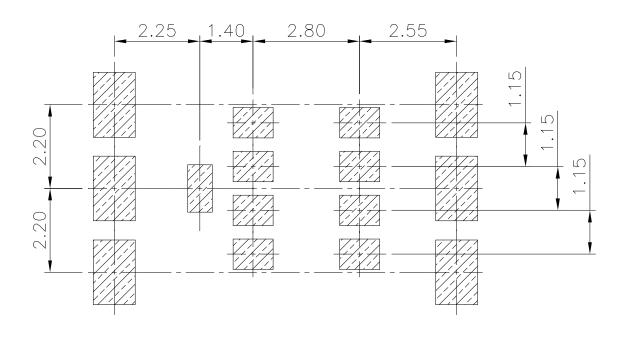


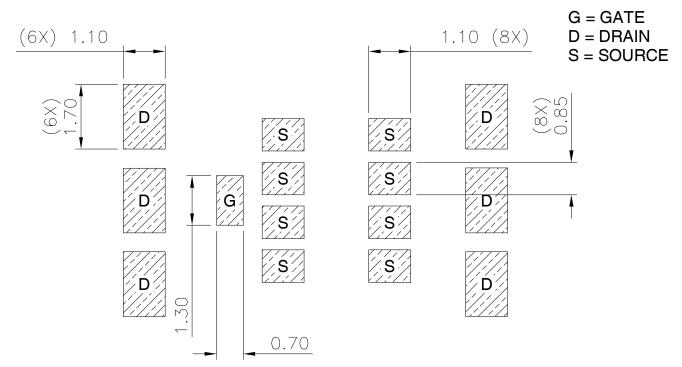
Fig 20b. Switching Time Waveforms



DirectFET™ Board Footprint, L8 (Large Size Can).

Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations



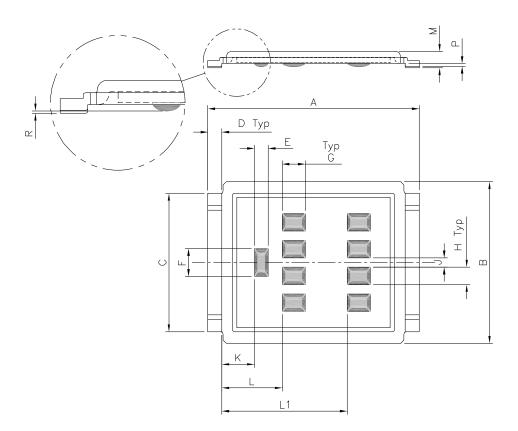


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



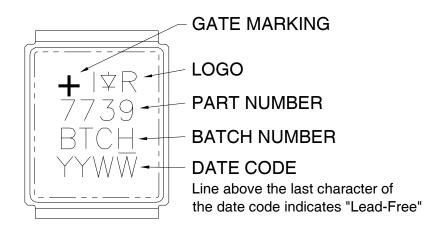
DirectFET™ Outline Dimension, L8 Outline (LargeSize Can).

Please see AN-1035 for DirectFET assembly details and stencil and substrate design recommendations



	DIMENSIONS						
	MET	TRIC	IMPE	RIAL			
CODE	MIN	MAX	MIN	MAX			
Α	9.05	9.15	0.356	0.360			
В	6.85	7.10	0.270	0.280			
С	5.90	6.00	0.232	0.236			
D	0.55	0.65	0.022	0.026			
E	0.58	0.62	0.023	0.024			
F	1.18	1.22	0.046	0.048			
G	0.98	1.02	0.039	0.040			
Н	0.73	0.77	0.029	0.030			
J	0.38	0.42	0.015	0.017			
K	1.35	1.45	0.053	0.057			
L	2.55	2.65	0.100	0.104			
L1	5.35	5.45	0.211	0.215			
М	0.68	0.74	0.027	0.029			
Р	0.09	0.17	0.003	0.007			
R	0.02	0.08	0.001	0.003			

DirectFET™ Part Marking

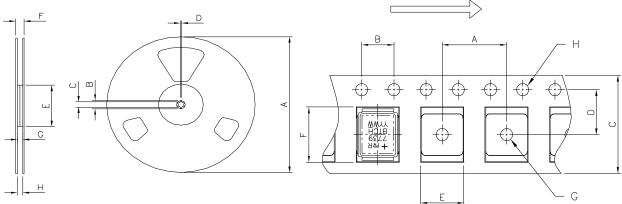


Note: For the most current drawing please refer to IR website at http://www.irf.com/package/



DirectFET™ Tape & Reel Dimension (Showing component orientation).

LOADED TAPE FEED DIRECTION



NOTE: Controlling dimensions in mm Std reel quantity is 4000 parts. (ordered as IRF7739L1TRPBF)

	REEL DIMENSIONS					
STANDARD OPTION (QTY 4000)						
	MET	METRIC IMPERIAL				
CODE	MIN	MAX	MIN	MAX		
Α	330.00	N.C	12.992	N.C		
В	20.20	N.C	0.795	N.C		
С	12.80	13.20	0.504	0.520		
D	1.50	N.C	0.059	N.C		
E	99.00	100.00	3.900	3.940		
F	N.C	22.40	N.C	0.880		
G	16.40	18.40	0.650	0.720		
Н	15.90	19.40	0.630	0.760		

NOTE: CONTROLLING DIMENSIONS IN MM

DIMENSIONS					
	MET	TRIC	IMPE	RIAL	
CODE	MIN	MAX	MIN	MAX	
Α	11.90	12.10	4.69	0.476	
В	3.90	4.10	0.154	0.161	
С	15.90	16.30	0.623	0.642	
D	7.40	7.60	0.291	0.299	
E	7.20	7.40	0.283	0.291	
F	9.90	10.10	0.390	0.398	
G	1.50	N.C	0.059	N.C	
Н	1.50	1.60	0.059	0.063	

Note: For the most current drawing please refer to IR website at http://www.irf.com/package/

Qualification Information[†]

Qualification level	Industrial †† *			
Moisture Sensitivity Level	DirectFET	MSL1		
		(per JEDEC J-STD-020D ^{†††})		
RoHS Compliant	Yes			

- † Qualification standards can be found at International Rectifier's web site http://www.irf.com/product-info/reliability
- †† Higher qualification ratings may be available should the user have such requirements. Please contact your International Rectifier sales representative for further information: http://www.irf.com/whoto-call/salesrep/
- **†††** Applicable version of JEDEC standard at the time of product release.

Revision History

Date	Comments
2/12/2013	TR1 option removed and Tape & Reel Info updated accordingly. Hyperlinks added throw-out the document

International **IOR** Rectifier

IR WORLD HEADQUARTERS: 101N Sepulveda Blvd, El Segundo, California 90245, USA

To contact International Rectifier, please visit http://www.irf.com/whoto-call/

^{*} Industrial qualification standards except autoclave test conditions

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WARNINGS

Due to technical requirements products may contain dangerous substances. For information on the types in question please contact your nearest Infineon Technologies office.

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